

Conductivity Study of CVD-diamond detectors

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Contributing...

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- ♣ M. Pomorski
- ♣ Detector Laboratory, GSI
- ♣ Target Laboratory, GSI

Outlines

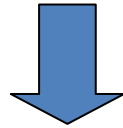
- ☐ **Introduction**
- ☐ ***I-V* characteristics of CVD Diamond Detectors**
- ☐ **Dark conductivity study of CVD Diamond materials**
 1. **Homoepitaxial CVD Diamonds, both sc and sc coating with DLC**
 2. **Heteroepitaxial quasi sc CVD Diamond on Ir (Dol)**
- ☐ **Summary**

Introduction

Electrical Conductivity

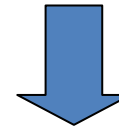
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graph TD; A[Electrical Conductivity] --> B[Electrode-Limited conduction]; A --> C[Bulk-Limited conduction]; B --> D["1. Schottky (Thermionic) emission<br/>2. Tunneling<br/>    (i) Direct Tunneling (DT)<br/>    (ii) Fowler Nordheim (FN)"]; C --> E["1. Space-charge limited conduction (SCLC)<br/>2. Poole-Frenkel (P-F) conduction<br/>3. Trap Assisted Tunneling (TAT)"];
```

Electrode-Limited conduction



1. Schottky (Thermionic) emission
2. Tunneling
 - (i) Direct Tunneling (DT)
 - (ii) Fowler Nordheim (FN)

Bulk-Limited conduction

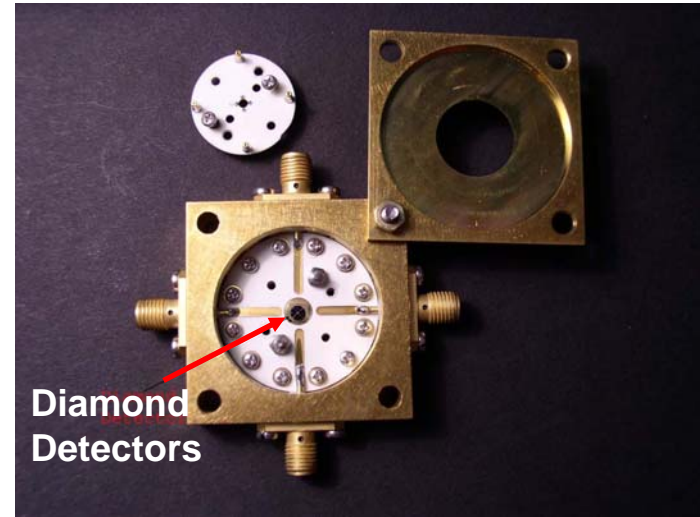


1. Space-charge limited conduction (SCLC)
2. Poole-Frenkel (P-F) conduction
3. Trap Assisted Tunneling (TAT)

Diamond Detectors

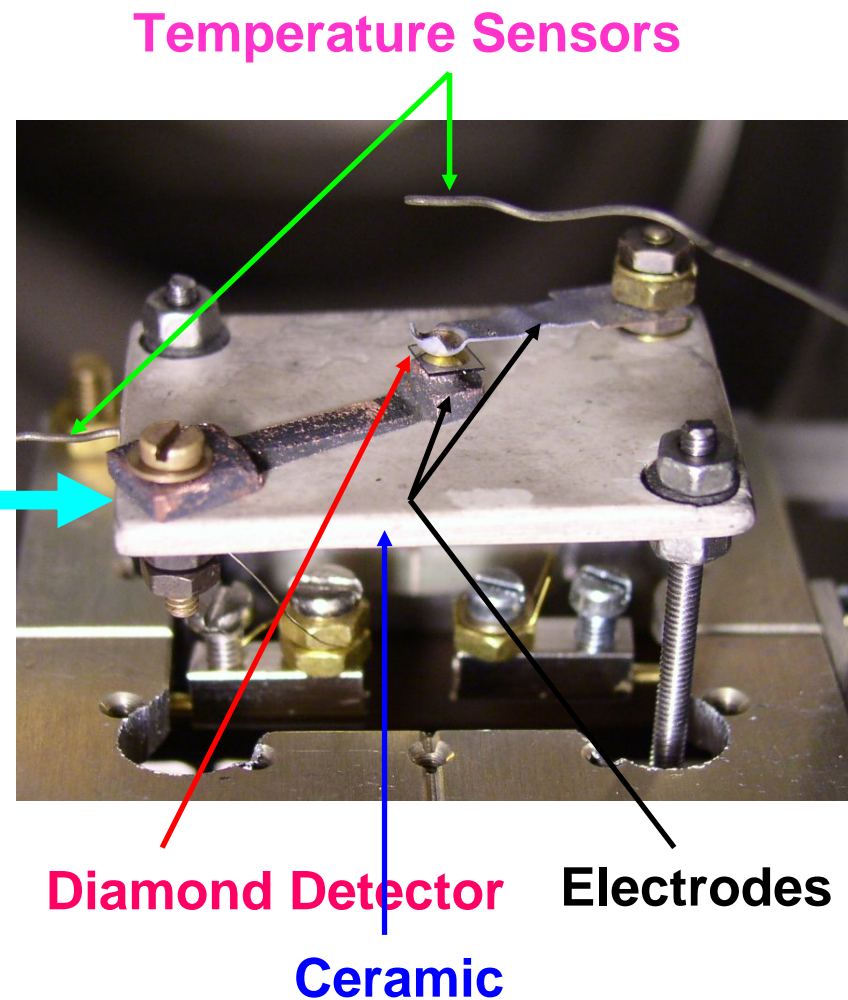
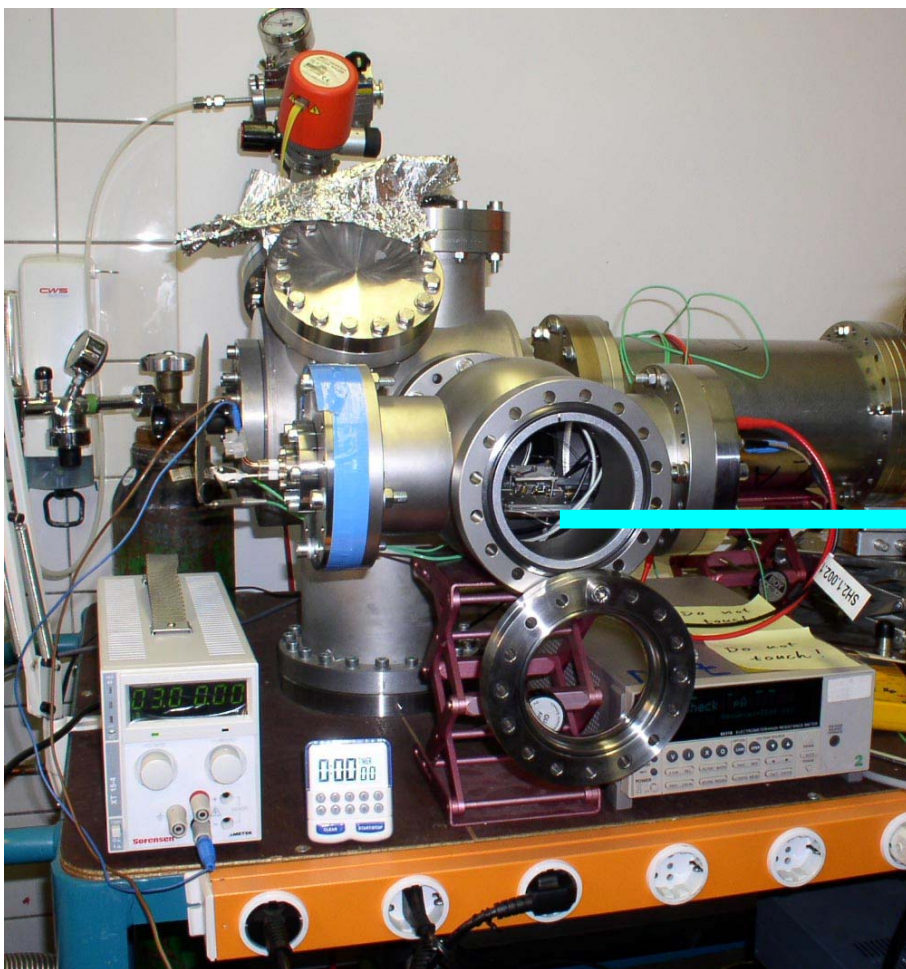


Diamond

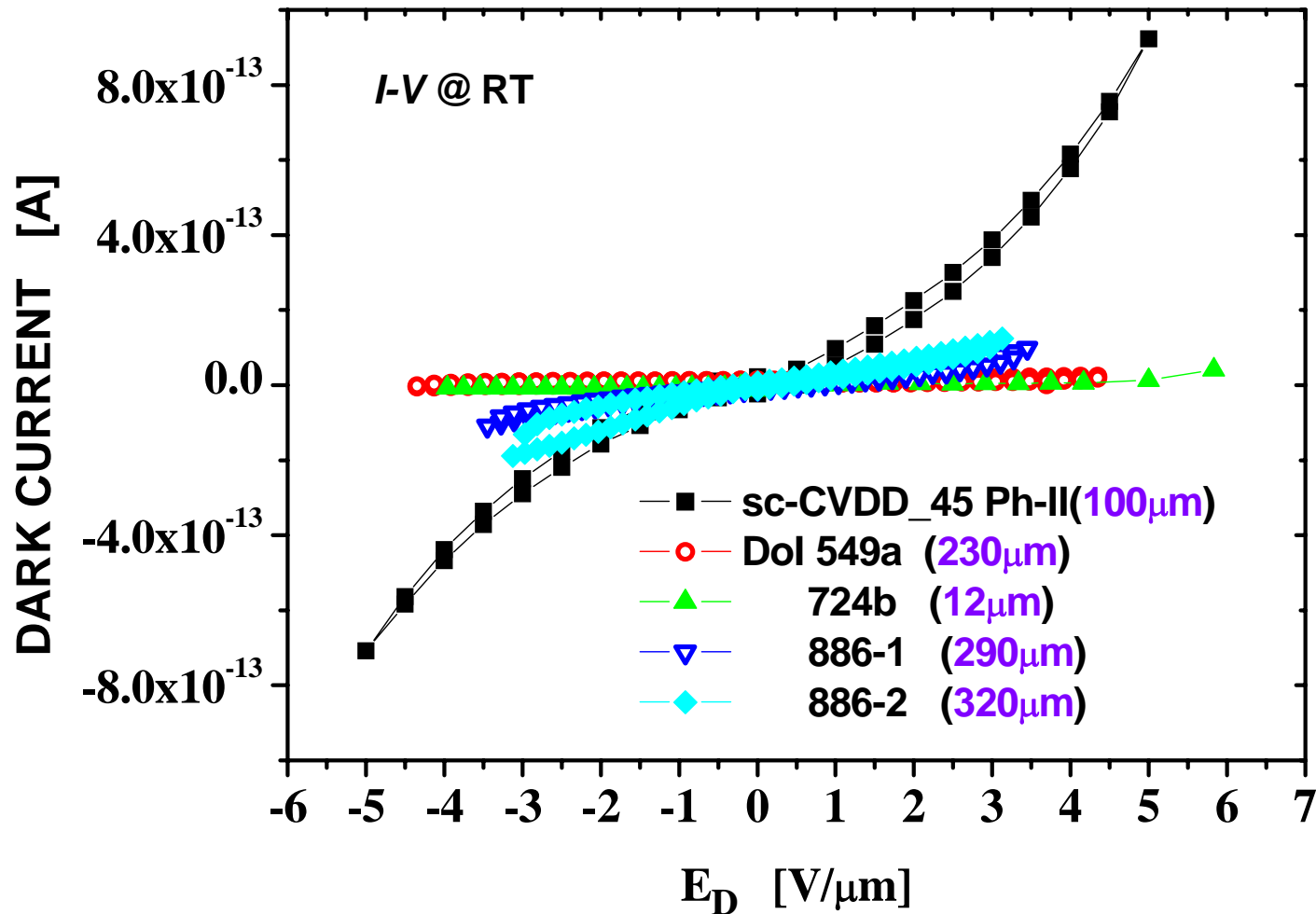


Diamond Detectors

Measurement setups

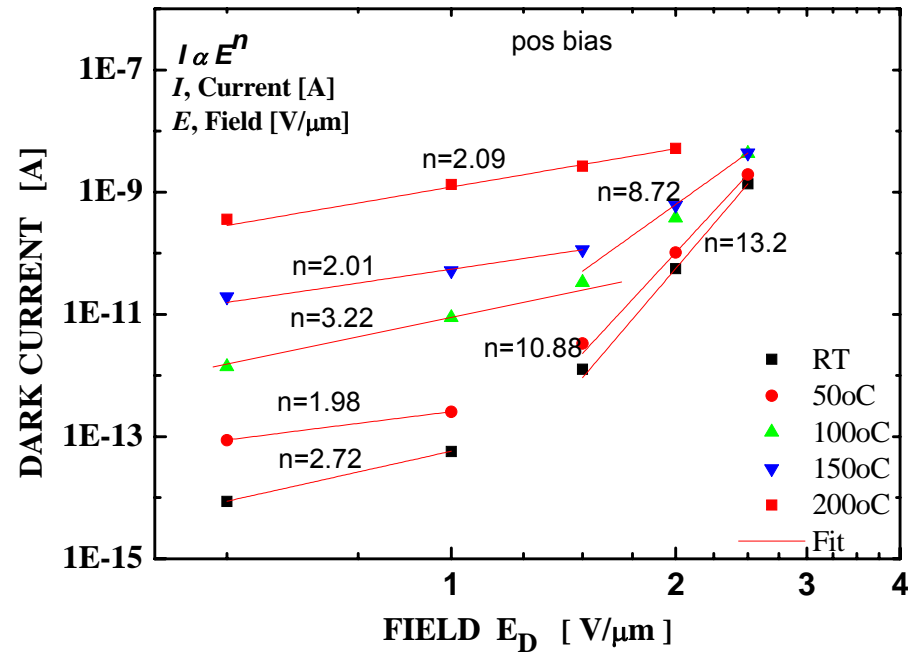
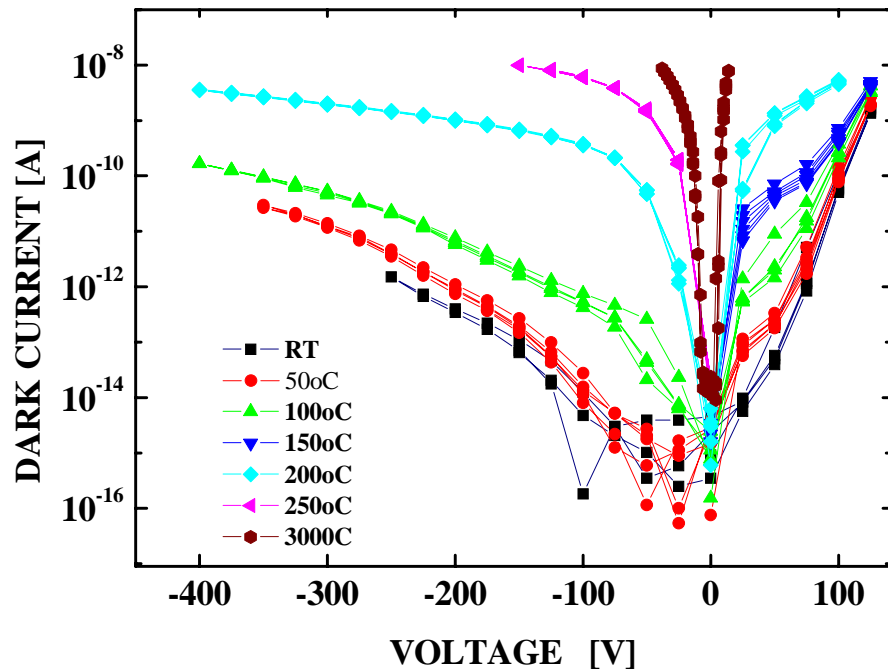


I-E characteristics CVDD Detectors



Electrical conduction of scCVDD

scCVDD 10B50 (50 μ m)
(Al-Dia-Al)

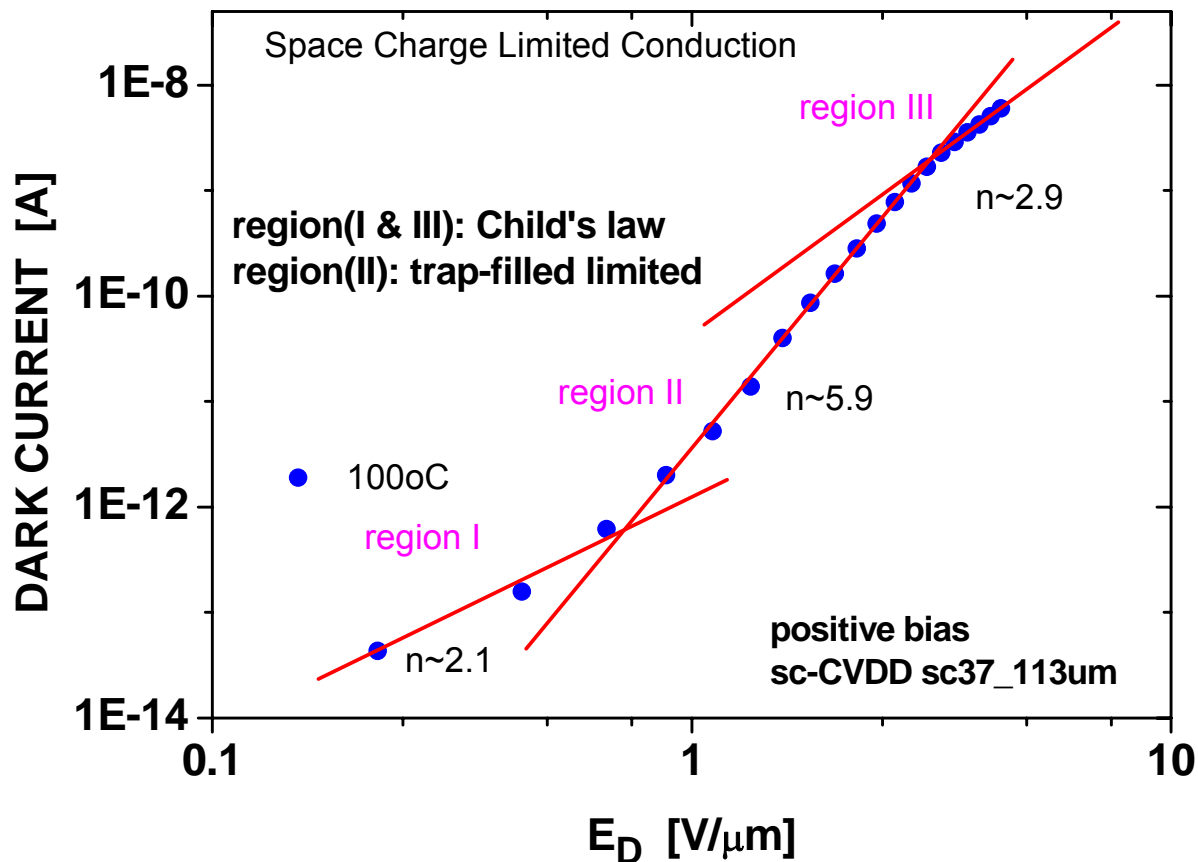


I-V characteristics at higher temp

I-E characteristics, SCLC

Space Charge Limited Conduction (SCLC)

sc37_113 μ m (Al/DLC-Dia-DLC/Al)



theory of SCLC

$$I_{Child} = \frac{9}{8} \mu \epsilon \frac{V^2}{d^3}$$

$$I_{TFL} = \frac{9}{8} \mu \epsilon \theta \frac{V^2}{d^3}$$

Here,

μ electronic mobility

V applied bias

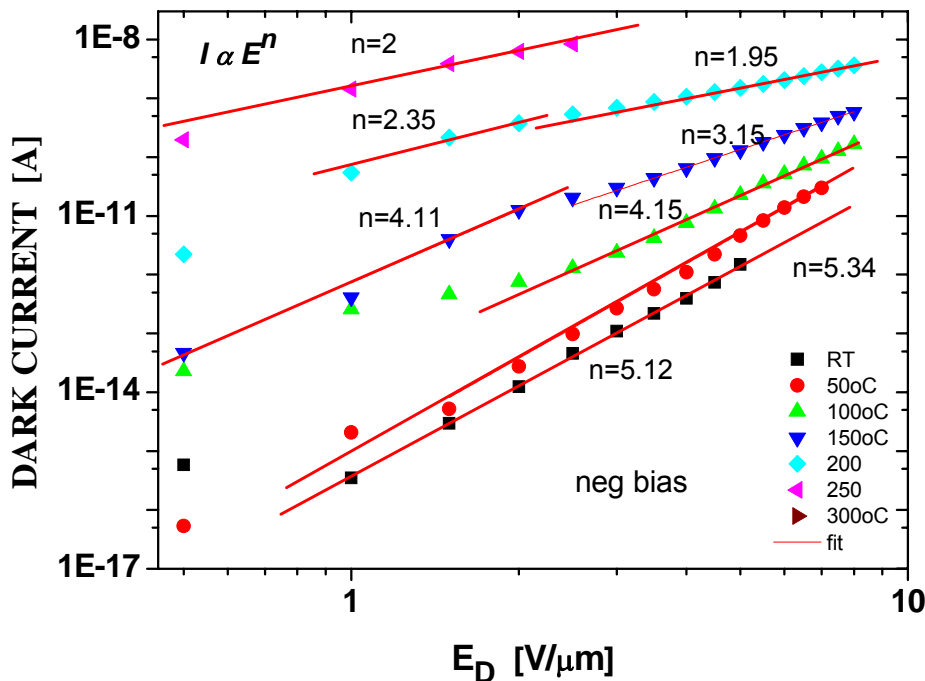
d thickness

ϵ dielectric constant

$$\theta = \frac{\text{free_Carrier_Density}}{\text{Total_Carrier_Density}}$$

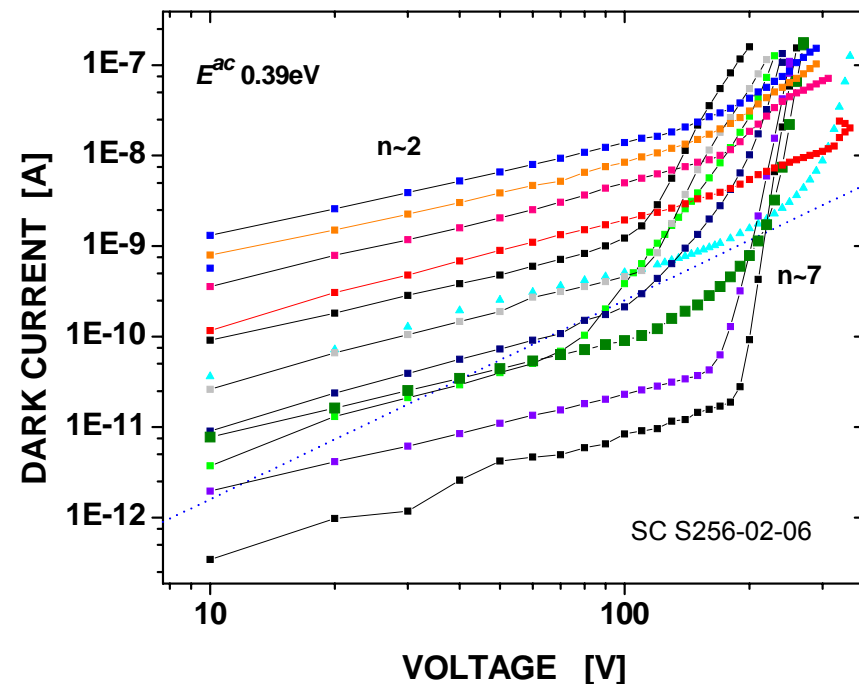
Electrical conduction of scCVDD

scCVDD 10B50 (50 μ m)
(Al-Dia-Al)



I-E characteristics, SCLC

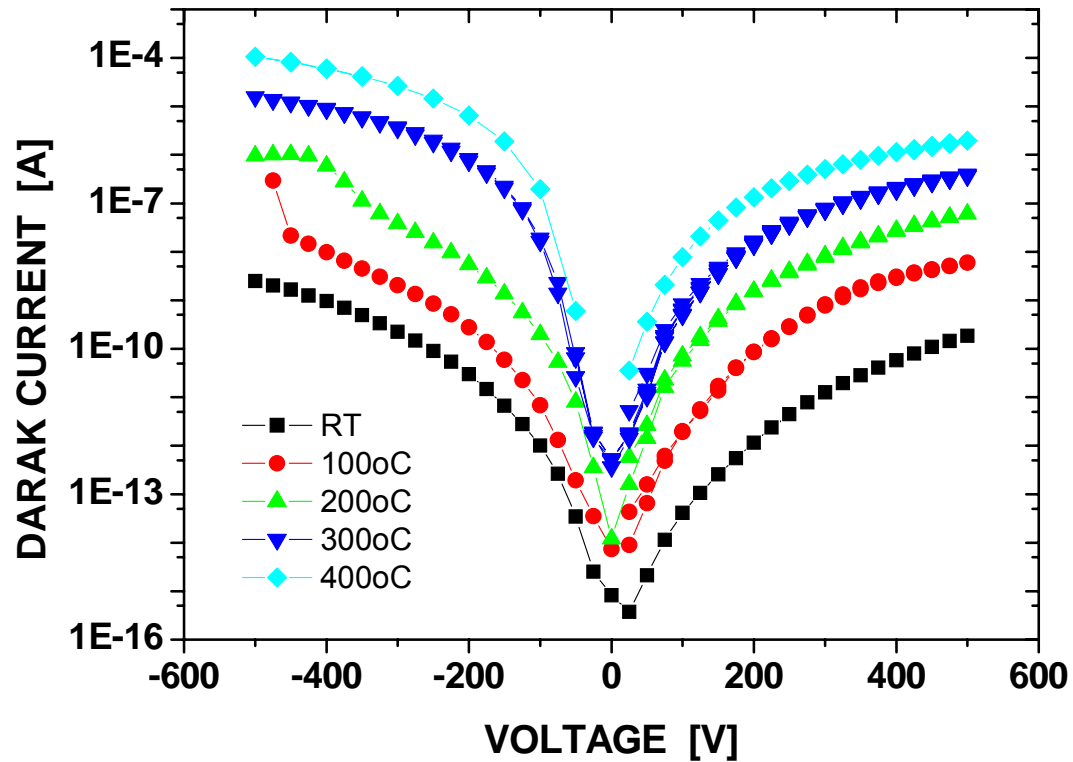
scCVDD s256-02-06



Michal Pomorski
PhD thesis 2008

I-V characteristics of scCVDD with DLC coating

sc37_113 μm
(Al/DLC-Dia-DLC/Al)



I-V characteristics at higher temp.

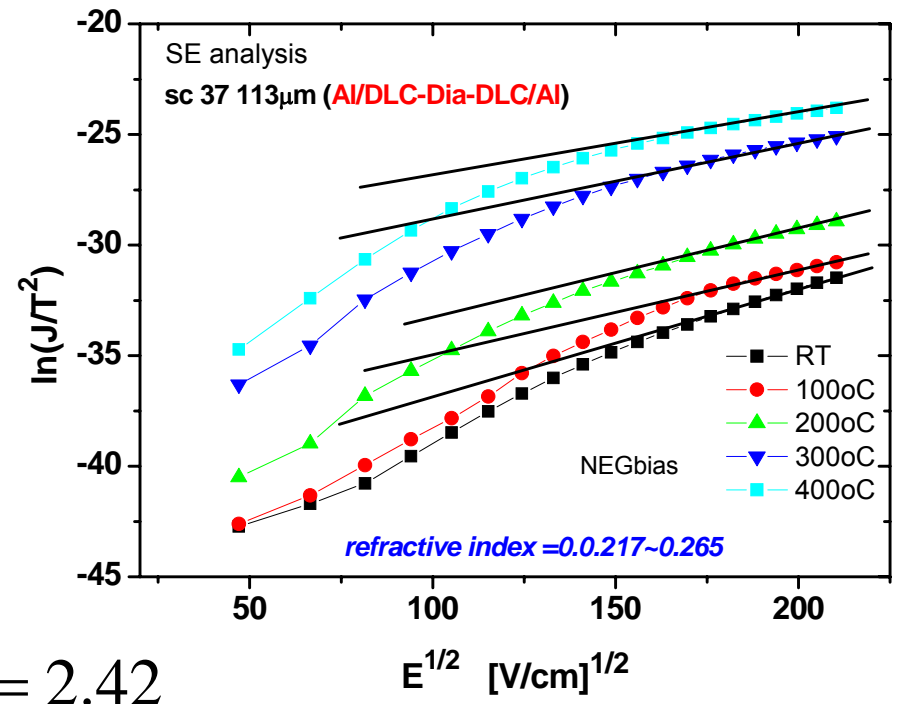
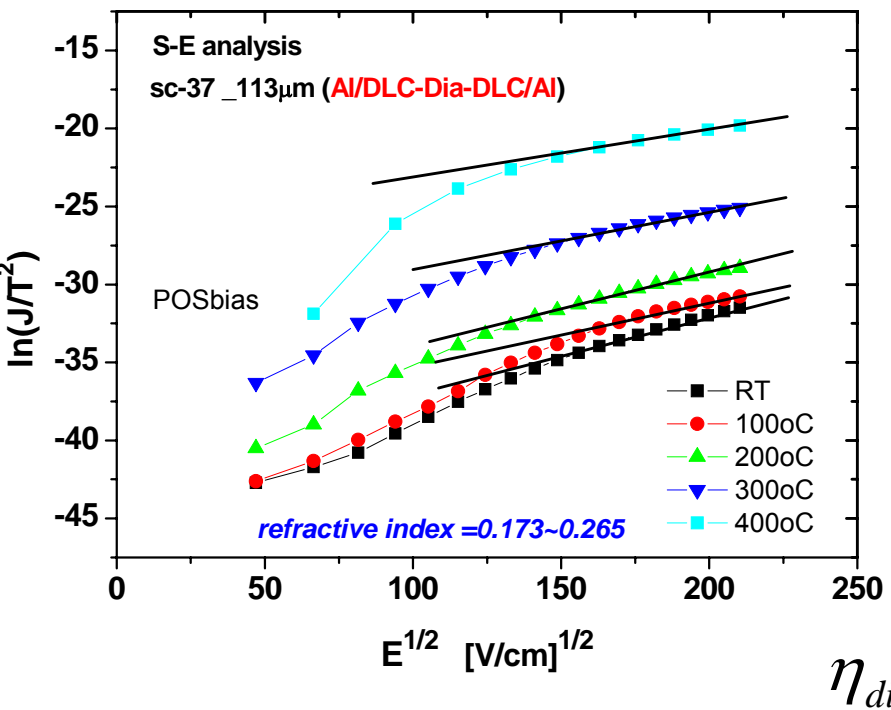
Electrical conduction of scCVDD with DLC coating

S-E

$$J = A^* T^2 \exp \left[\frac{-q(\phi_b - \sqrt{qE_D / 4\pi\kappa_d \epsilon_o})}{k_b T} \right]$$

$$\ln(J / T^2) \propto E_D^{1/2} \quad \eta^2 = \kappa_d$$

scCVDD sc37 (113 μ m)
(Al/DLC-Dia-DLC/Al)



Schottky emission (S-E) conduction ? **NO**

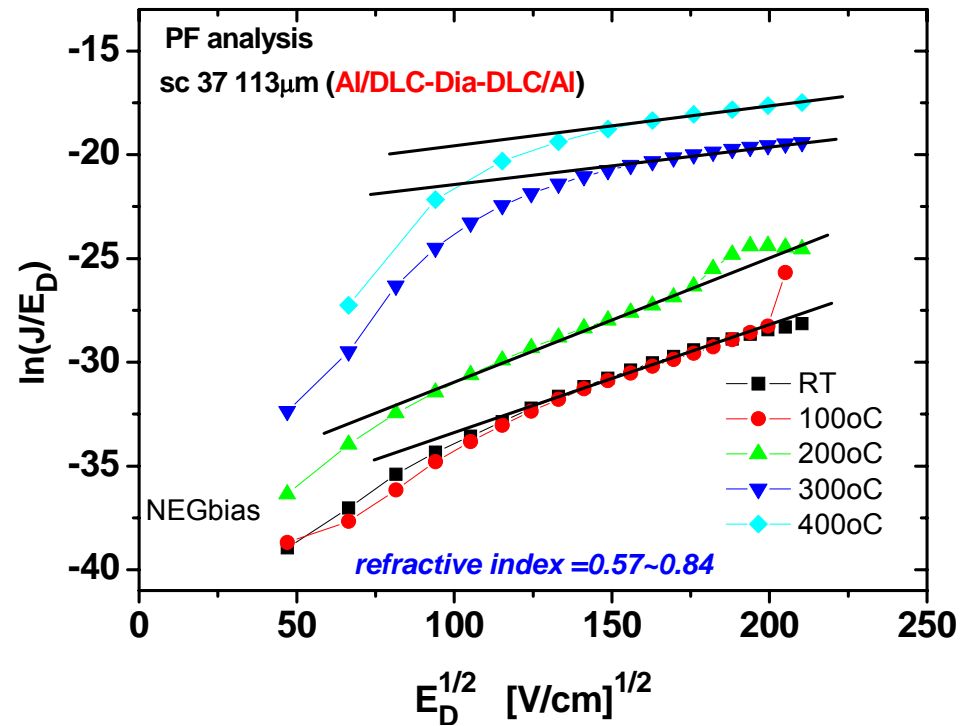
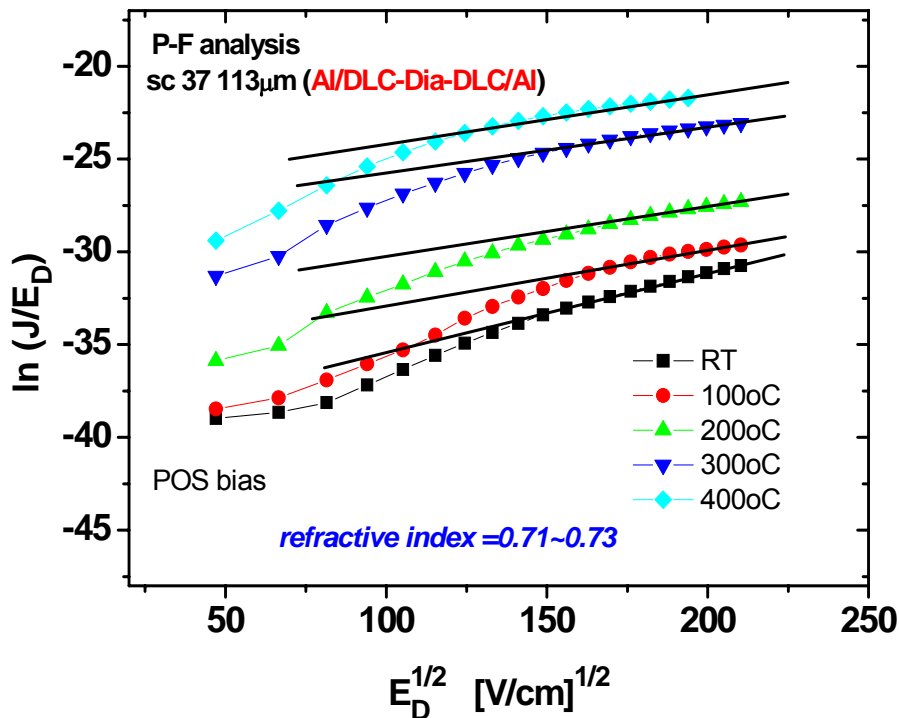
Electrical conduction of scCVDD with DLC coating

P-F

$$J = C_t E_D \exp \left[\frac{-q(\phi_t - \sqrt{qE/\pi\kappa_d \epsilon_o})}{k_b T} \right]$$

$$\ln(J / E_D) \propto E_D^{1/2} \quad \eta^2 = \kappa_d$$

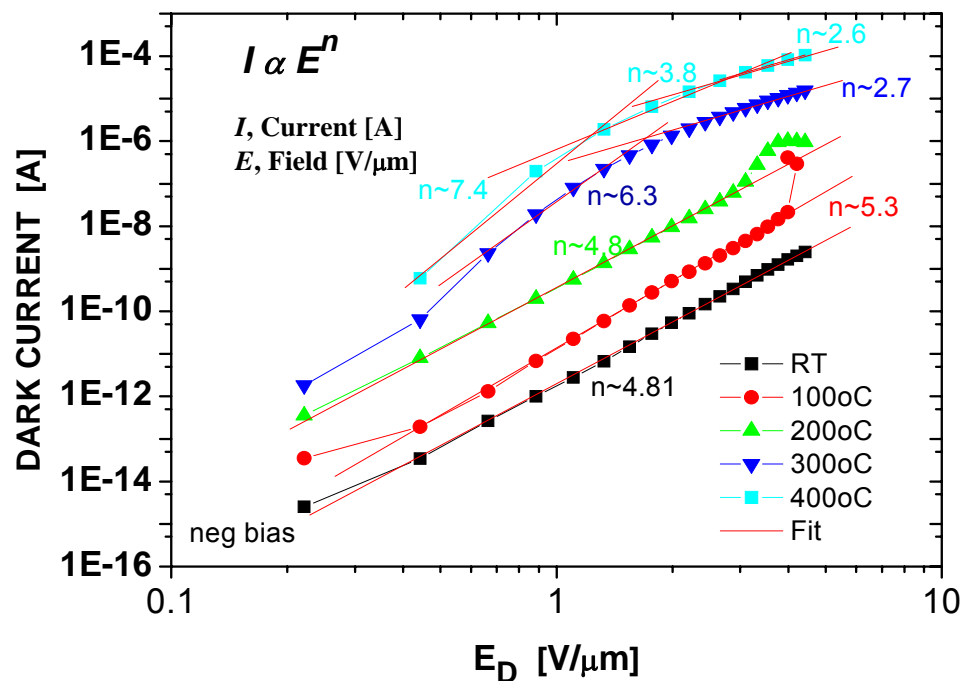
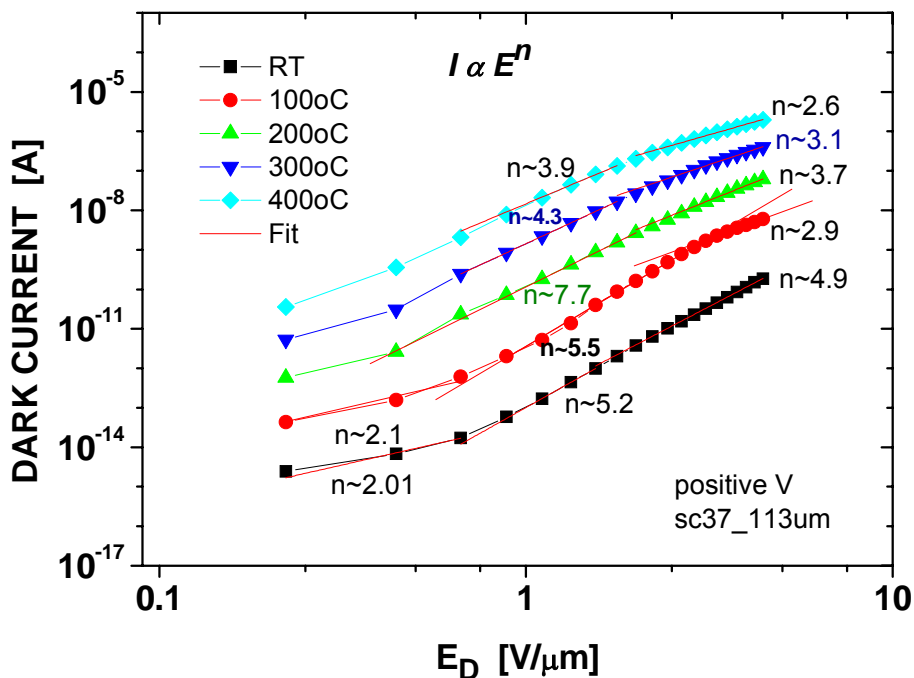
scCVDD sc37 (113 μ m)
(AI/DLC-Dia-DLC/AL)



Poole-Frenkel (P-F) conduction ? **NO**

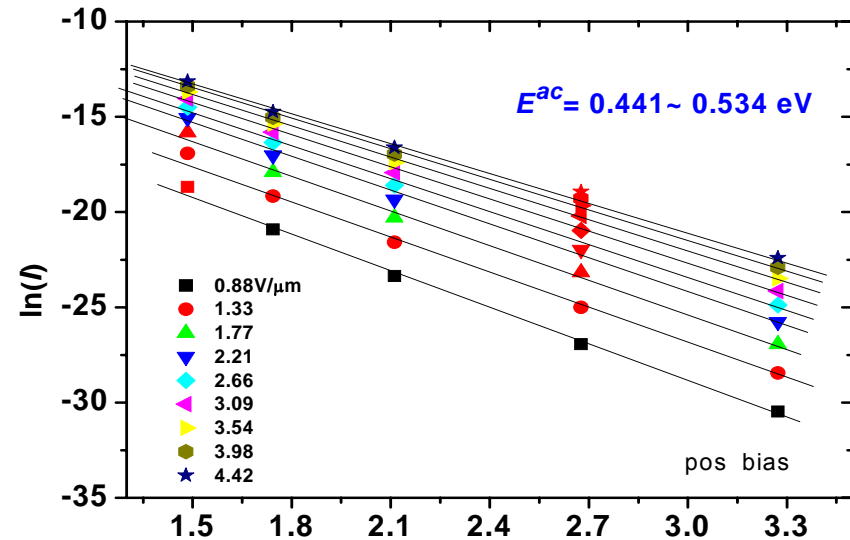
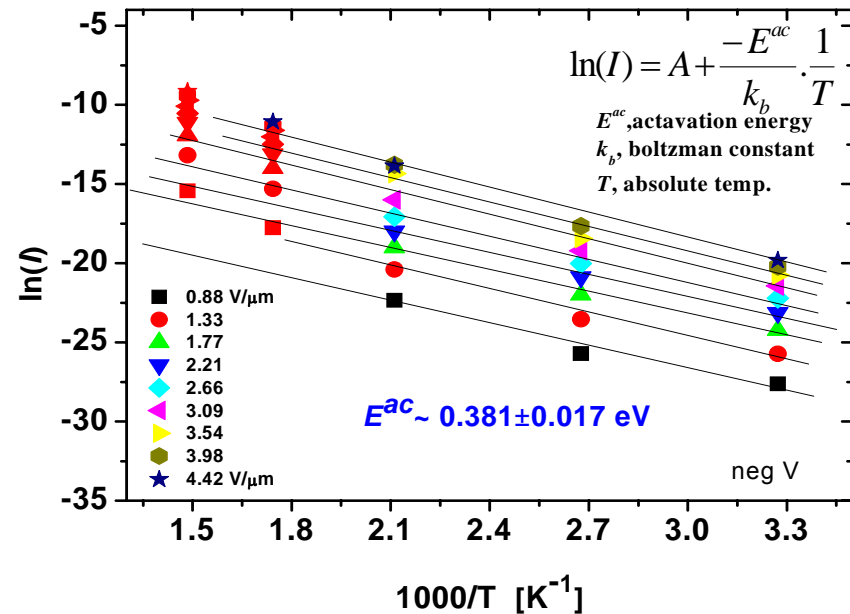
Electrical conduction of scCVDD with DLC coating

scCVDD sc37 (113 μ m)
(Al/DLC-Dia-DLC/Al)

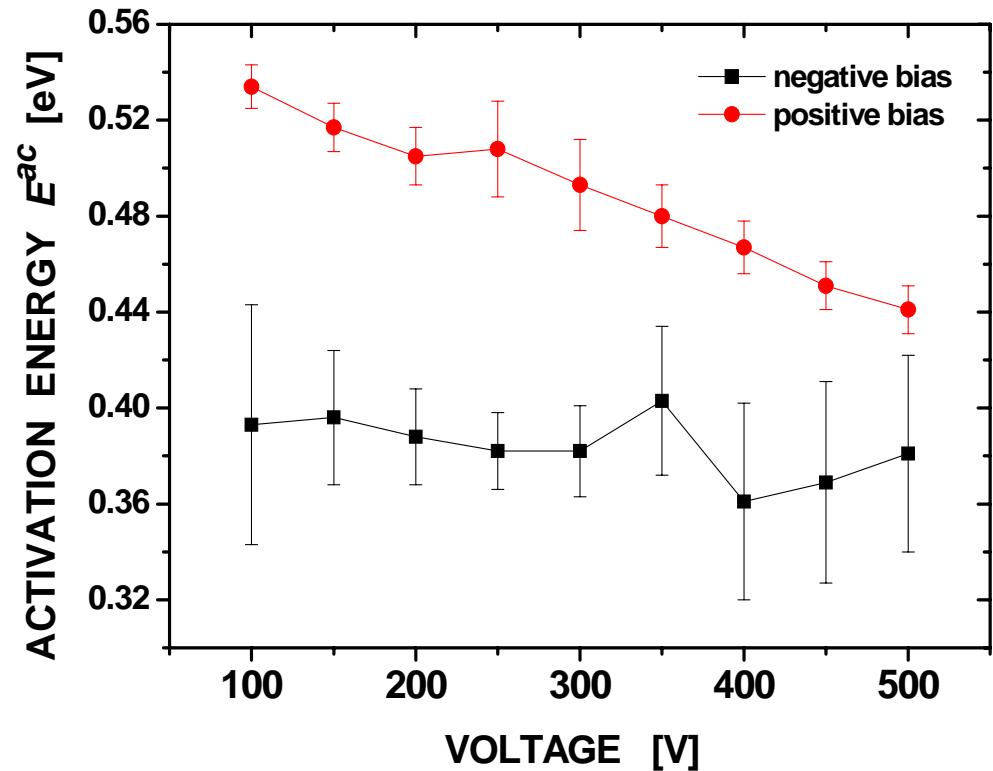


I-E characteristics, SCLC

E^{ac} of scCVDD with DLC coating



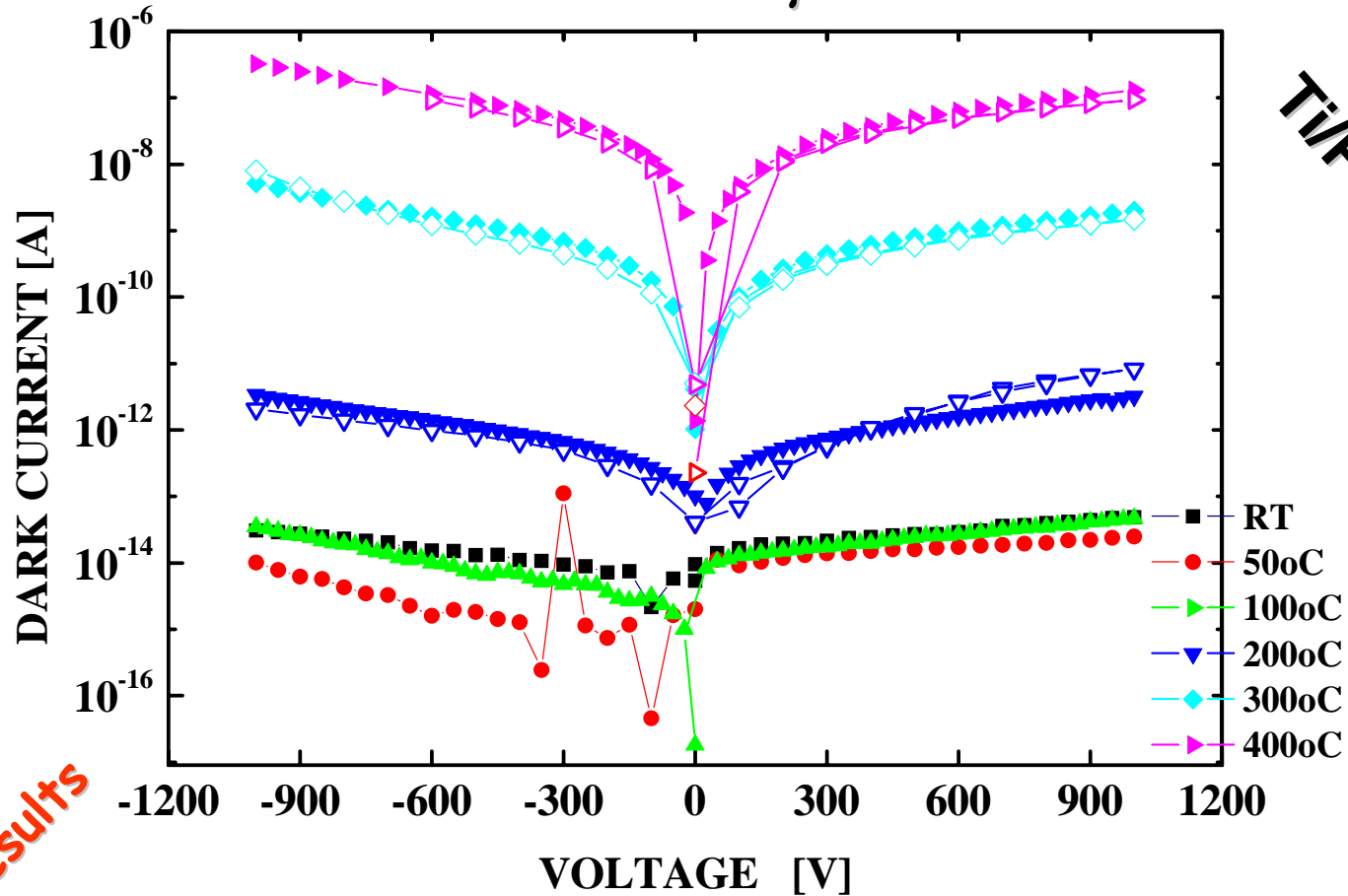
scCVDD sc37 _ 113mm
(AI/DLC-Dia-DLC/AI)



Activation Energy of the trap

I-V characteristics of Early DoI

DoI 549a 230 μm



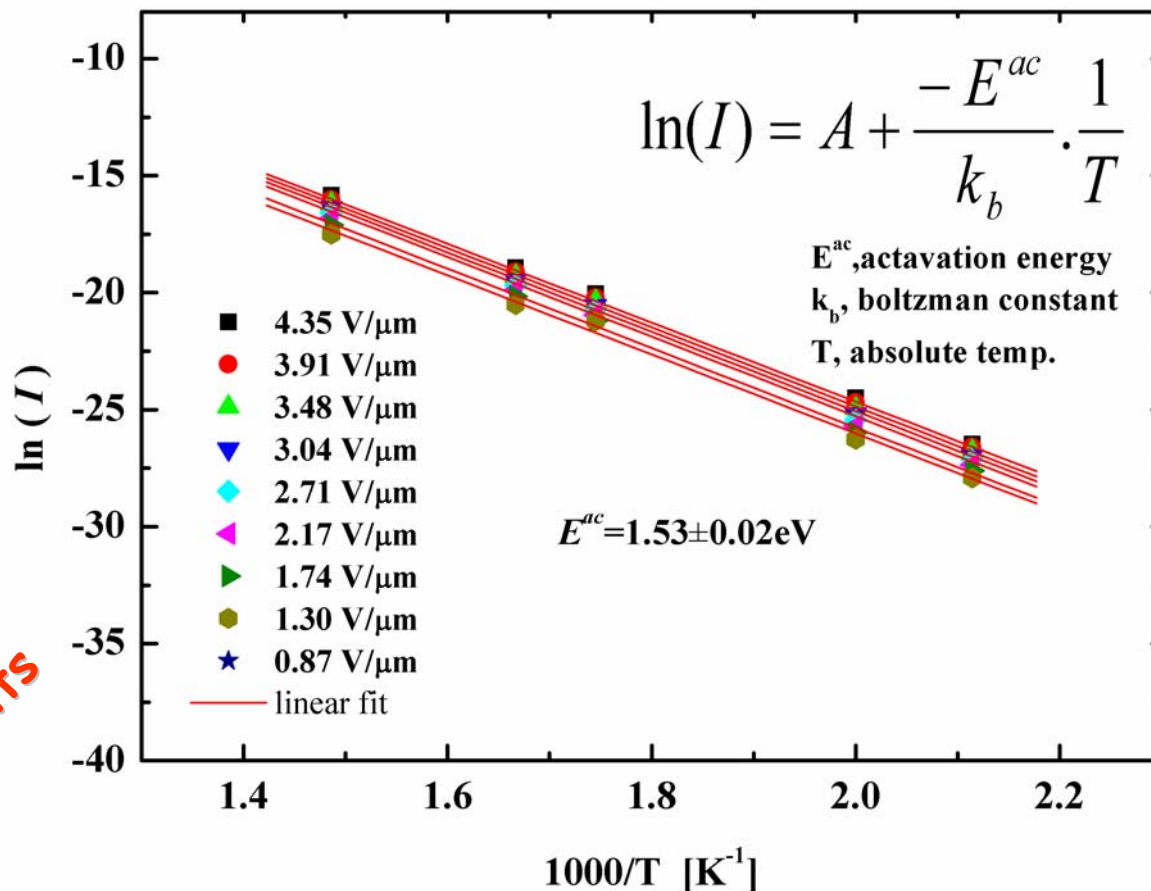
Ti/Pt/Au & Al

Early Results

I-V characteristics at higher temp.

Activation energy of Early DoI

DoI 549a 230 μ m



Early Results

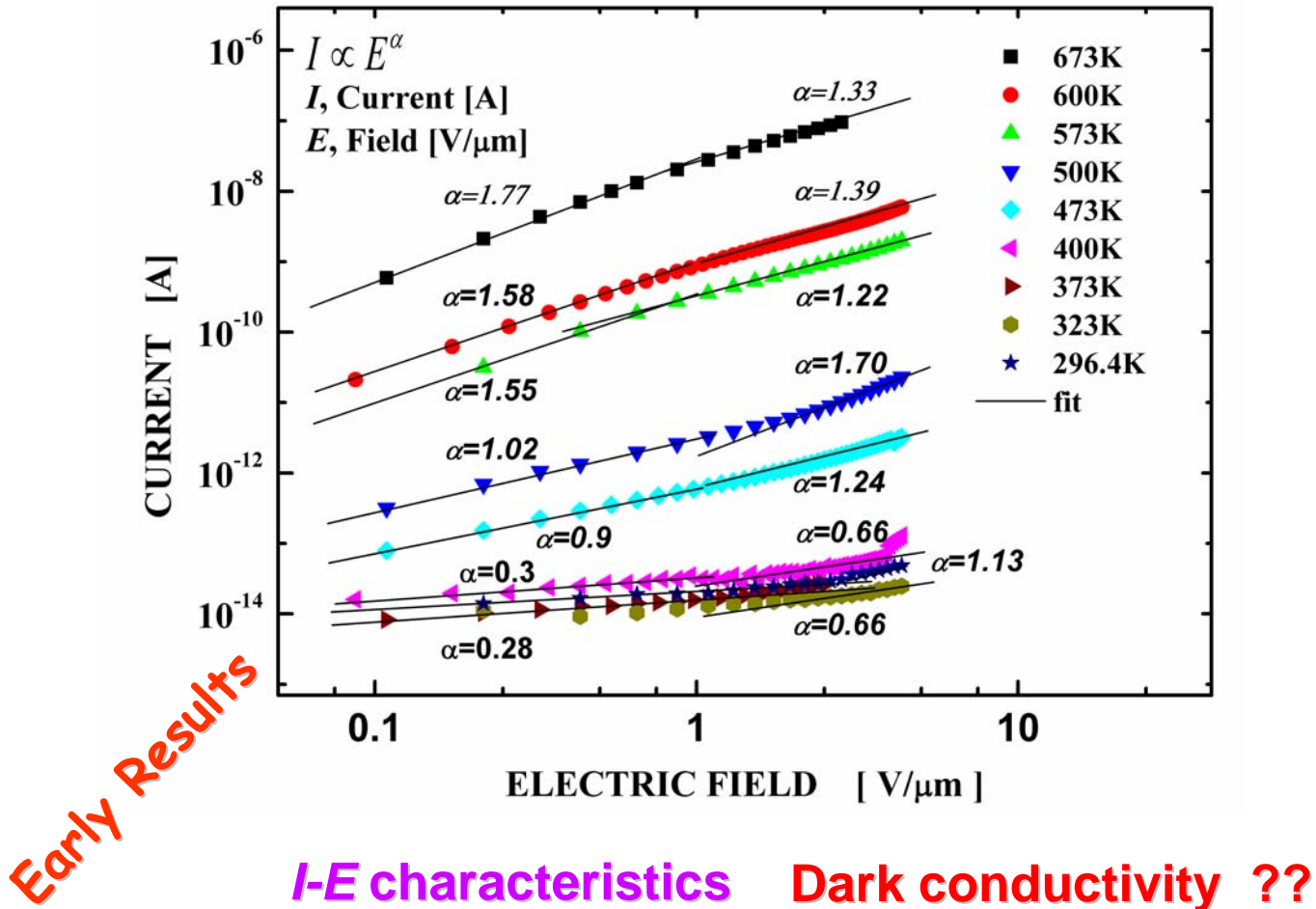
Ti/Pt/Au & Al

Activation Energy of traps $E^{ac} = 1.53 \pm 0.01 \text{ eV}$

Ref. $E^{ac} = 1.4 \text{ eV}$; A. Stolz, et al., DRM 2006

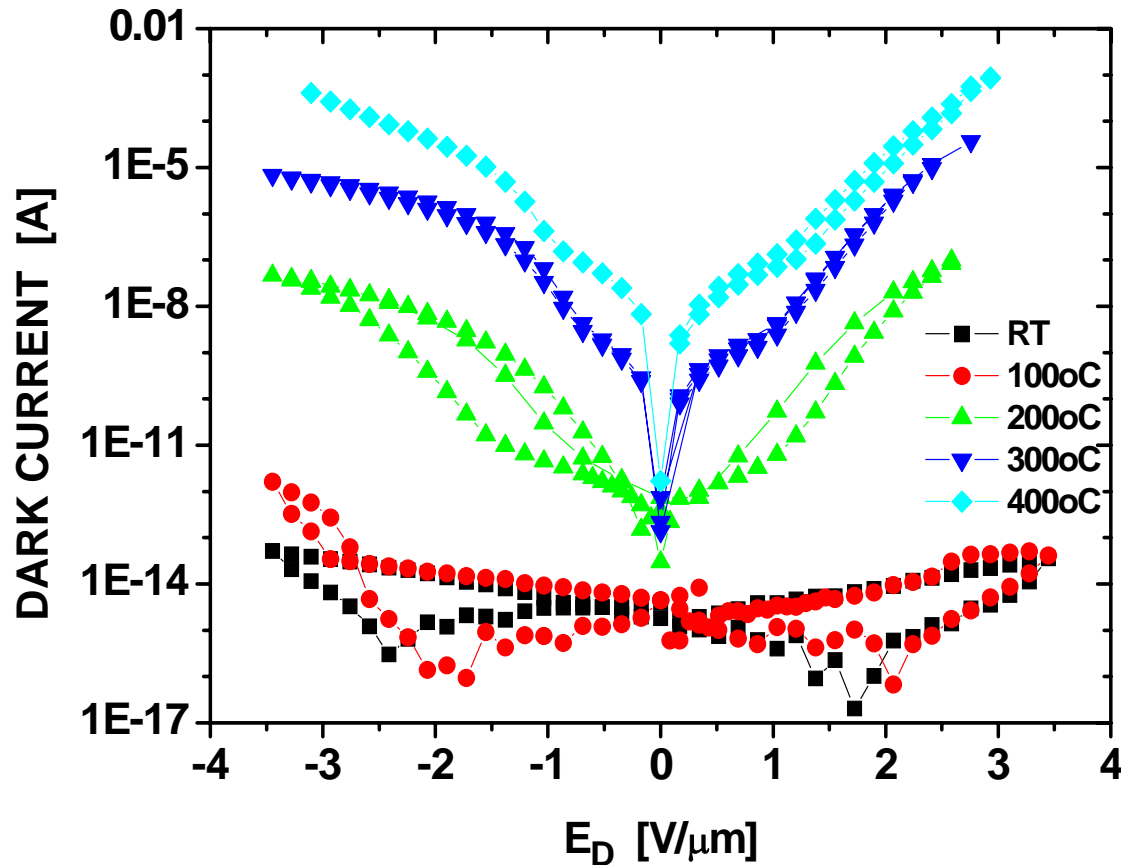
Electrical conduction of early DoI

DoI 549a 230 μm



Electrical ($I-E$) Characteristics of DoI

DoI 886-1 290 μm



I-V characteristics at higher temp.

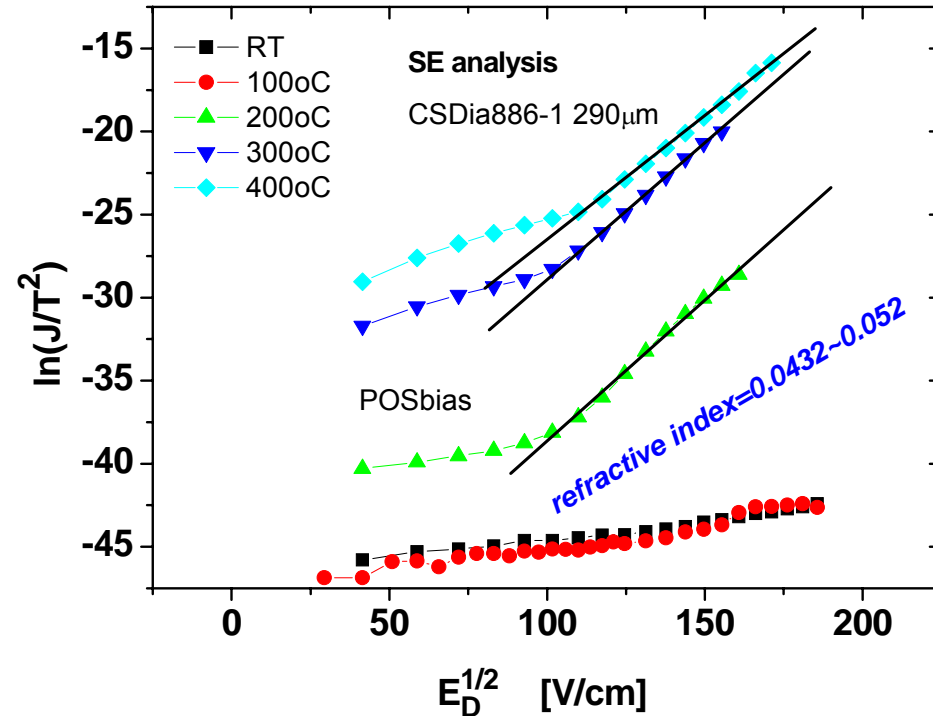
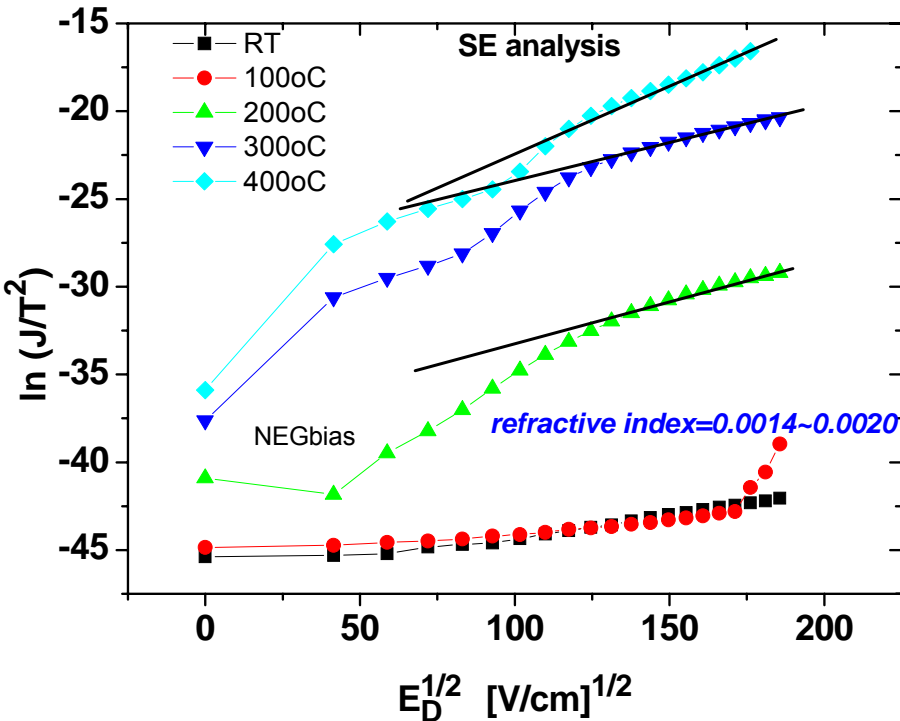
Electrical conduction of DoI

S-E

$$J = A^* T^2 \exp \left[\frac{-q(\phi_b - \sqrt{qE_D / 4\pi\kappa_d \epsilon_o})}{k_b T} \right]$$

$$\ln(J / T^2) \propto E_D^{1/2} \quad \eta^2 = \kappa_d$$

DoI 886-1 290 μ m



Schottky emission (S-E) conduction ? **NO**

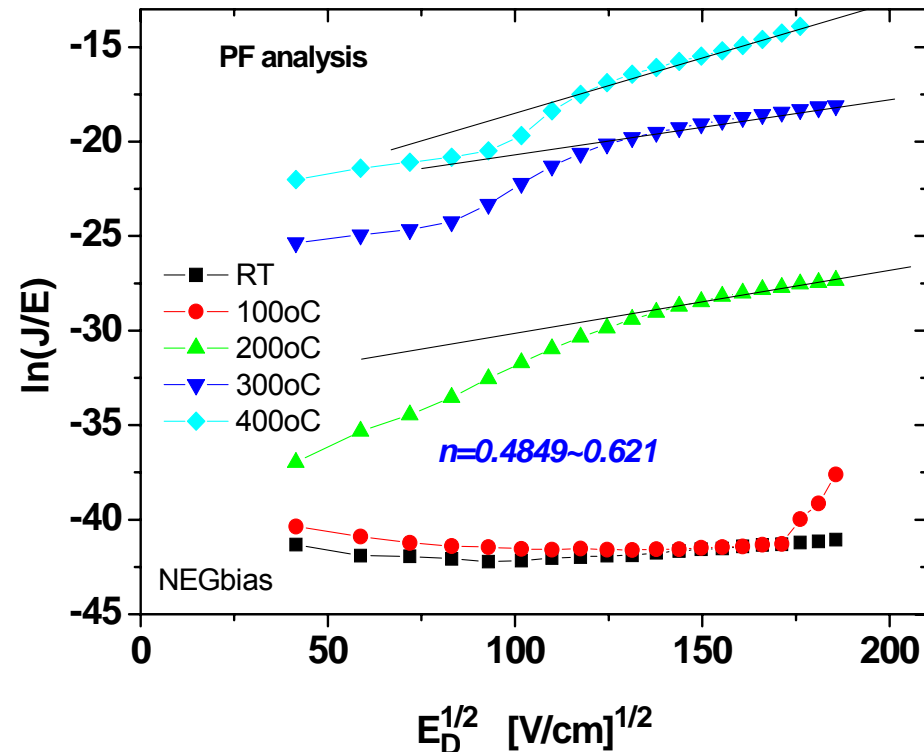
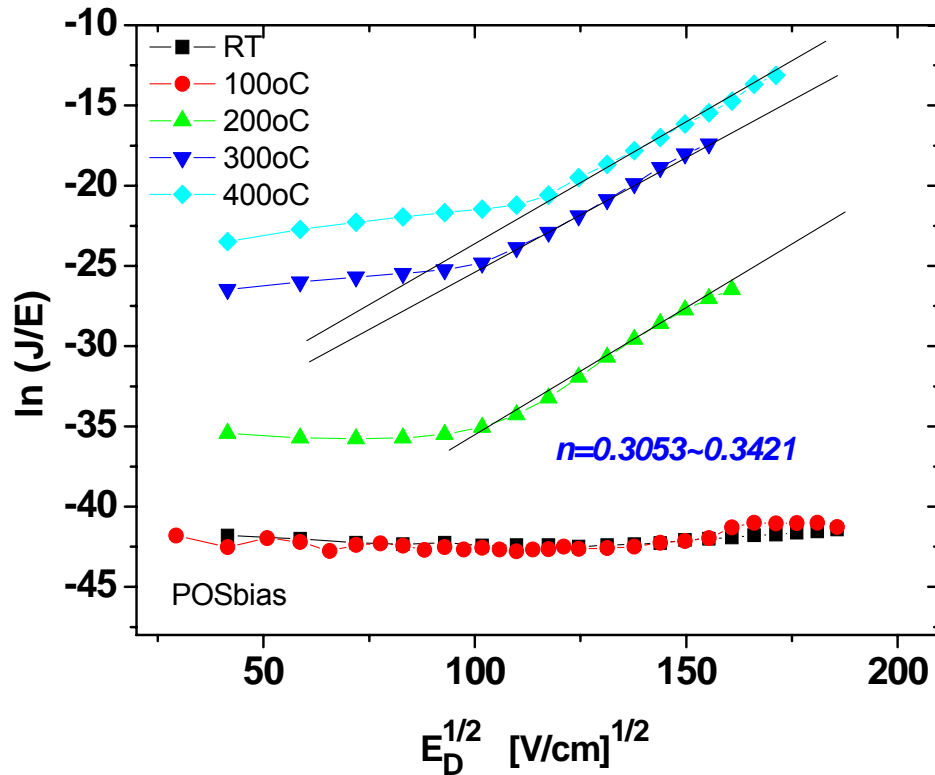
Electrical conduction of DoI

P-F

$$J = C_t E_D \exp \left[\frac{-q(\phi_t - \sqrt{qE/\pi\kappa_d \epsilon_o})}{k_b T} \right]$$

$$\ln(J / E_D) \propto E_D^{1/2} \quad \eta^2 = \kappa_d$$

DoI 886-1 290 μ m

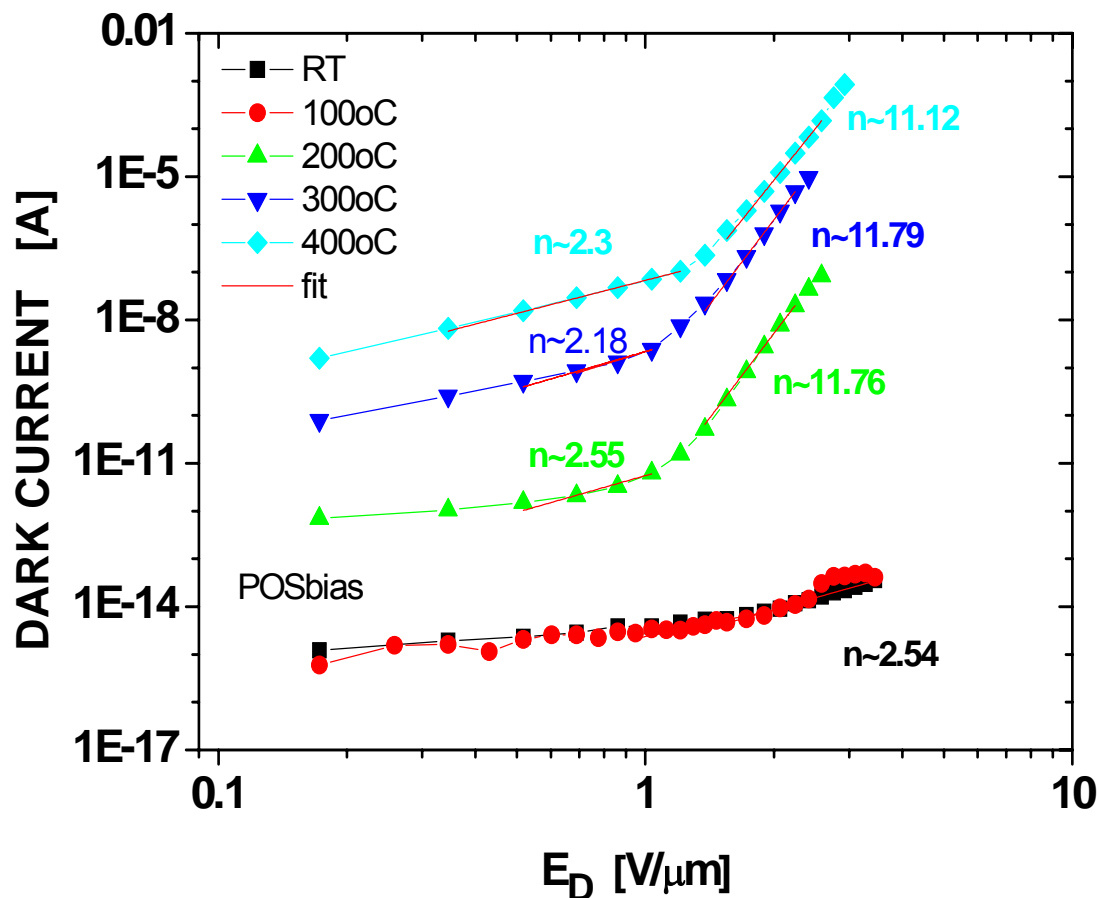


Poole-Frenkel (P-F) conduction ?

NO

Electrical conduction of DoI

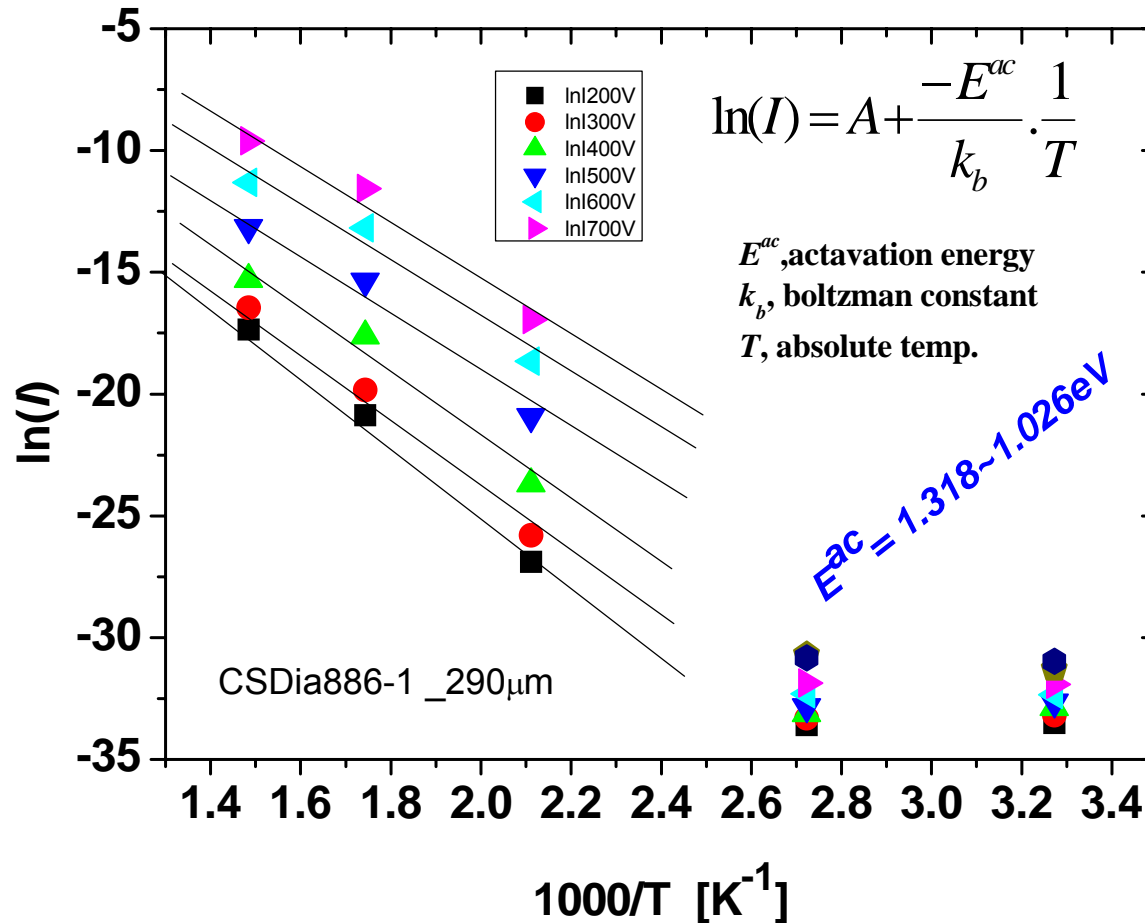
DoI 886-1 290 μm



I-E characteristics, SCLC

Electrical conduction of DoI

DoI 886-1 290 μm



Activation Energy of the trap level

Summary

- Electrical (I - V) characteristics of scCVDD detector are analyzed
- The dominant dark current conductivity of scCVDD detector is SCLC
- The activation energy level of the trap is $0.37\sim 0.39\text{eV}$
- After coating scCVDD with DLC the conductivity remains the same, *i.e.*, SCLC and the activation energy is $(0.38 \pm 0.017)\text{eV}$ at negative bias while at positive bias $E^{ac}=0.44\sim 0.54\text{eV}$
- The DoI show SCLC mechanism with an activation energy of $E^{ac}=1.32\sim 1.026\text{eV}$

Thank you for your attention